超大型積體電路測試 VLSI testing Homework I



國立情華大學

系所:電子所碩一

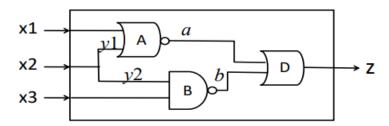
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1.Consider the testing of a gate-level circuit as shown below. The primary input signals are {x1, x2, x3} and the primary output signal is {z}. The output signals of logic gates {A, B} are denoted as {a, b}, and the branches of primary input signal x2 is called y1 and y2, respectively.



(a) Write a software program (using C, C++, or any other programing language) that can exhaustively simulate the logic behavior of the given circuit under each of the 2 3 = 8 input vectors). Note that this can be done by executing the following Boolean equations in sequence in your program:

```
a = \sim (x1 \text{ or } x2);

b = \sim (x2 \text{ and } x3);

z = (a \text{ or } b);
```

List the results as a truth table for output signal z. (Note this truth table contains 8 entries, one for each input combination).

Truth table & Code

```
#include <stdio.h>
#include <stdlib.h>
correct circuit
                                                  void printBinary(int btd, char binary[])
x1 x2 x3
                        a
                                                     sprintf(binary, "%s", "");
for (int i = 0; i >= 0; i--) {
    sprintf(binary, "%s%d", binary, (btd >> i) & 1);
                                            0
       0
               0
                        1
                             1
                                 1
                                                 int main()
                        1
0
       0
               1
                             1
                                  1
                                                     int a, b, z;
char binary_a[2], binary_b[2], binary_z[2];
printf("correct circuit\n");
printf("x1 x2 x3| a b z\n");
printf("------\n");
0
       1
               0
                        0
                             1
               1
                        0
0
       1
                             0
                                  0
                                                     0
                        0
                             1
1
       0
                                  1
1
       0
               1
                        0
                             1
                                 1
1
       1
               0
                        0
                             1 1
1
       1
               1
                        0
                            0 0
```

(b) Enhance your program so that it can perform exhaustive fault simulation for bridging faults, {AND-bridging between a and b} and {OR-bridging between y1 and x3}. Note that you need to report the total number of possible test patterns for each of the above two bridging faults. (Hint: perform fault injection, run exhaustive simulation on the faulty circuit, and then compare the results with those of the fault-free circuit. The fault injection can be done manually by changing the compiled code.)

Truth table

```
correct circuit
   x2 x3
           a b z
   0
       0
0
       1
0
   0
0
   1
       0
0
   1
       1
            0
1
   0
       0
           0
              1 1
1
   0
       1
           0
             1 1
1
   1
       0
            0
             1 1
   1
       1
           0
             0 0
AND-bridging fault
x1 x2 x3
           abz
0
   0
       0
           1
                1 V
0
   0
       1
0
   1
       0
            0
                0
   1
       1
0
            0
       0
1
   0
            0
              0
       1
1
   0
            0
              0
   1
       0
            0
              0
1
       1
           0 0 0 V
AND-bridging fault number:4
OR-bridging fault
x1 x2 x3 | a b z
0
   0
       0
0
       1
       0
           0
0
   1
0
   1
       1
           0
             0
1
       0
   0
            0
             1 1 V
1
   0
       1
            0
              1
                1 V
1
   1
       0
           0
             0 0 X
   1
       1
           0 0 0 V
OR-bridging fault number:2
```

只比較輸出Z,正確的後面為V,錯誤的為X

Code

```
1 #include <stdio.h>
2 #include <stdlib.h>
3
                  sprintf(binary, "%s", "");
for (int i = 0; i >= 0; i --) {
    sprintf(binary, "%s%d", binary, (btd >> i) & 1);
                  tmain()
int x1, x2, x3, y1, y2, a, b, z, c, d, e, f, g, h;
int AND_bridging fault_number, OR_bridging fault_number=0;
char binary_s[2], binary_b[2], binary_z[2], binary_a2[2], binary_b2[2], binary_z2[2])
printf("cxt x2 x3] a b z \( \)"
printf("x1 x2 x3] a b z \( \)"
for(int x1=0; x1<-1; x1++)
for(int x1=0; x3<-1; x2++) {
    for(int x2=0; x2<-1; x2++) {
        if a = -(x1 | x2)
        b = -(x2 & x3)
        z = -(x1 | x2)
        b = -(x2 & x3)
        z = -(a | b);
        z = (a | b);
        printfinary(a, binary_a), printfinary(b, binary_b), printfinary(z, binary_z);
        printf("Xd Xd Xd | %s Xs Xs\n", x1, x2, x3, binary_a, binary_b, binary_z);
    }
}</pre>
                 }
printf("AND-bridging fault number:%d\n", AND_bridging_fault_number);
                  else(
printf("%d %d %d | %d %d %d %\n", x1, x2, x3, e, f, h);
OR_bridging_fault_number = OR_bridging_fault_number=1;
                                  else(
    printf("%d %d %d %d %d %d %\n", x1, x2, x3, e, f, h);
    On_bridging_fault_number = On_bridging_fault_number+1;
}
                   printf("OR-bridging fault number:%d\n", OR_bridging_fault_number); return 0;
```

Discussion

本次作業我使用C語言來完成此邏輯閘的真值表。

因為 AND-bridging fault 的原因,所以當 a 或 b 有任意一個為 0 時,就會將另一個也變為 0,就是 AND 閘的概念,所以本題的輸出只會有 0 或 1,在 bridging 後原本的 OR 閘也等於無效,就不會產生 a 和 b 不同但輸出 Z 卻相同的情況。

因為 OR-bridging fault 的原因,所以當 x1 或 y1 有任意一個為 1 時,就會將另一個也變為等同於在中間加了 OR 閘,但這會產生一個問題,如果只單純看 z 輸出的值與原本相同,可能中間的 a 和 b 點也要檢測錯誤的話會不一樣,例如(x1,x2,x3)=(0,0,1)時,正確的(a,b,z)=(1,1,1),但 OR-bridging 後會變成(a,b,z)=(0,1,1),可以看出 a 從 1 變 0 了,但因為本題只做 z 判斷,故將這個邏輯中的差別寫在下面討論。